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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/086,127	BACH ET AL.	
Examiner	Art Unit	
Jia W. Lu	2634	

	SEARCHED			
Class	Subclass	Date	Examiner	
375	346	5/23/2005	JL	
356	453	5/23/2005	JŁ	
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INTERFERENCE SEARCHED		
Subclass	Date	Examiner
346	5/27/2005	JL
	Subclass	Subclass Date

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	5/23/2005	JL
INVENTORSHIP	5/27/2005	JL
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